

## [DTM: Degraded Test Mode for Fault-Aware Probabilistic Timing Analysis](#)

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**Publication:** 25th Euromicro Conference on Real-Time Systems (ECRTS13)

**Place Published:** Paris, France

**Palabras clave:** [Aerospace electronics](#), [Cache memory](#), [critical real-time embedded systems](#), [CRTES](#), [Degradation](#), [degraded test mode](#), [DTM](#), [Embedded systems](#), [fault tolerant computing](#), [fault-aware probabilistic timing analysis](#), [fault-tolerance](#), [fault-tolerant hardware designs](#), [Hardware](#), [hardware fault rates](#), [hardware modifications](#), [low energy budgets](#), [performance requirements](#), [Probabilistic logic](#), [probabilistic timing analysis](#), [probability](#), [smaller transistors](#), [system temporal behaviour](#), [Testing](#), [tight WCET estimates](#), [Timing](#), [Transistors](#), [trustworthy WCET estimates](#), [wcet](#), [WCET analysis tools](#), [worst-case execution time](#), [worst-case performance degradation](#)

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